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ion scattering spectrometry (ISS)

Any technique using low energy (10 keV) ions in which the bombarding particles scattered by the sample are detected and recorded as a function of energy and/or angle. This technique is used mainly for determining the composition and structure of the first few atomic layers of a sample.

Source:
PAC, 1979, *51*, 2243 *(General aspects of trace analytical methods - IV. Recommendations for nomenclature, standard procedures and reporting of experimental data for surface analysis techniques)* on page 2246